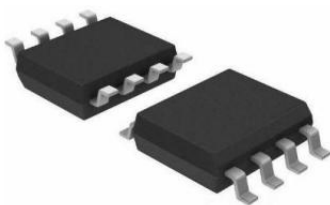
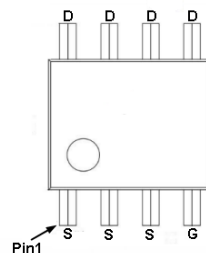
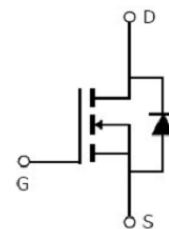


## Main Product Characteristics

$V_{DSS}$	100V
$R_{DS(on)}$	8m $\Omega$ (typ.)
$I_D$	60A ①


**SOP-8**

**Pin Assignment**

**Schematic Diagram**

## Features and Benefits

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



## Description

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

## Absolute Max Rating

Symbol	Parameter	Max.	Units
$I_D @ T_A = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ①	60	A
$I_D @ T_A = 70^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ①	42	
$I_{DM}$	Pulsed Drain Current ②	20	
$P_D @ T_A = 25^\circ\text{C}$	Power Dissipation ③	3.1	W
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy @ $L=0.3\text{mH}$	12	mJ
$I_{AS}$	Avalanche Current	9	A
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

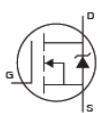
## Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	24	°C/W
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10s$ ) ④	—	40	°C/W

## Electrical Characterizes @ $T_A=25^\circ C$ unless otherwise specified

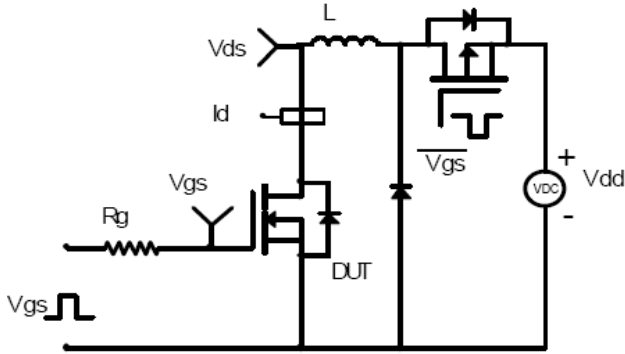
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	100	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	8	12	m $\Omega$	$V_{GS}=10V, I_D=11.5A$
		—	12	15.5		$V_{GS}=4.5V, I_D=9.5A$
$V_{GS(th)}$	Gate threshold voltage	1.2	—	2.5	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu A$	$V_{DS} = 80V, V_{GS} = 0V$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
$Q_g$	Total gate charge	—	35	—	nC	$I_D = 11.5A,$ $V_{DS}=50V,$ $V_{GS} = 10V$
$Q_{GS}$	Gate-to-Source charge	—	7.8	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	3.9	—		
$t_{d(on)}$	Turn-on delay time	—	8.8	—	nS	$V_{GS}=10V, V_{DD} = 50V,$ $R_{GEN}=3\Omega$ $I_D = 11.5A$
$t_r$	Rise time	—	4.4	—		
$t_{d(off)}$	Turn-Off delay time	—	34.8	—		
$t_f$	Fall time	—	5.3	—		
$C_{iss}$	Input capacitance	—	2550	—	pF	$V_{GS} = 0V$ $V_{DS} = 50V$ $f = 1MHz$
$C_{oss}$	Output capacitance	—	306	—		
$C_{rss}$	Reverse transfer capacitance	—	13	—		

## Source-Drain Ratings and Characteristics

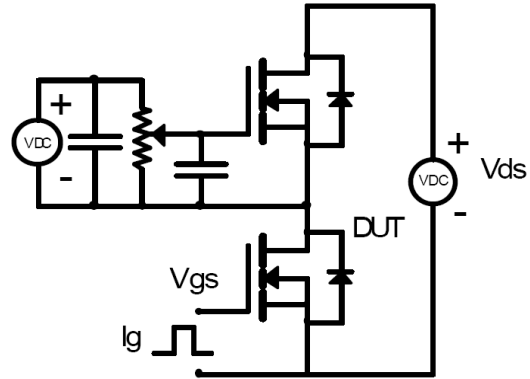
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode) ①	—	—	4	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$V_{SD}$	Diode Forward Voltage	—	—	1.1	V	$I_S=1A, V_{GS}=0V, T_J = 25^\circ C$
$t_{rr}$	Reverse Recovery Time	—	30	—	nS	$T_J = 25^\circ C, I_F = 11.5A,$ $di/dt = 100A/\mu s$
$Q_{rr}$	Reverse Recovery Charge	—	120	—	nC	

## Test Circuits and Waveforms

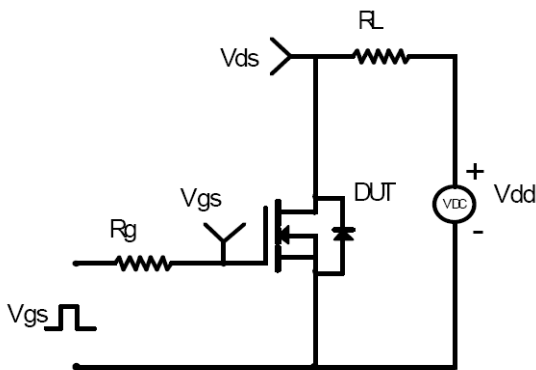
EAS Test Circuit:



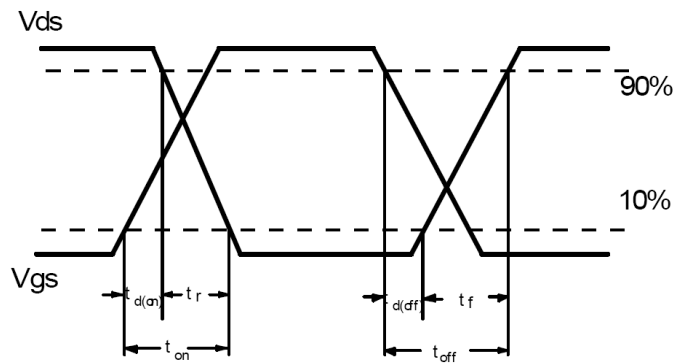
Gate Charge Test Circuit:



Switching Time Test Circuit:



Switching Waveforms:



### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

Typical Electrical and Thermal Characteristics

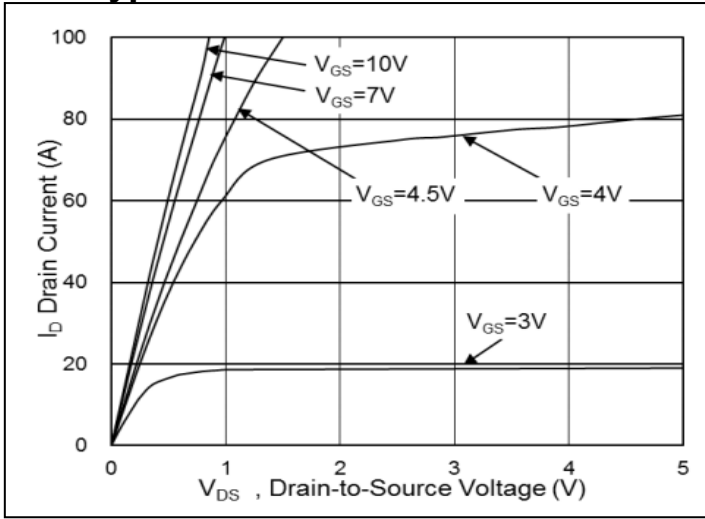


Figure1. Typical Output Characteristics

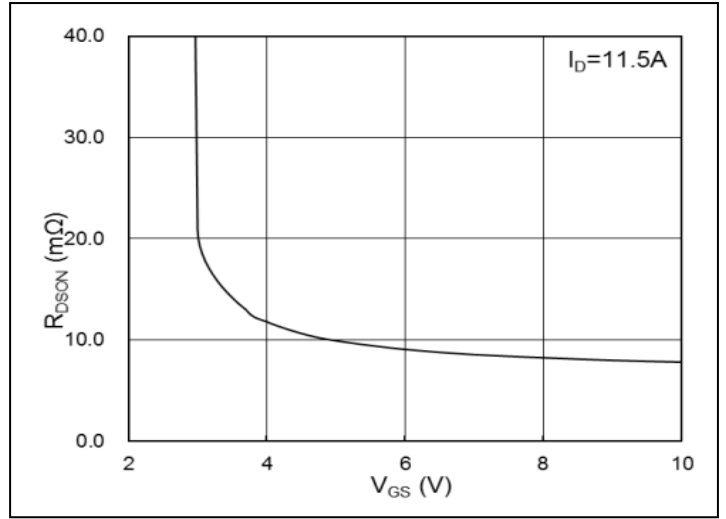


Figure2. On-Resistance vs. G-S Voltage

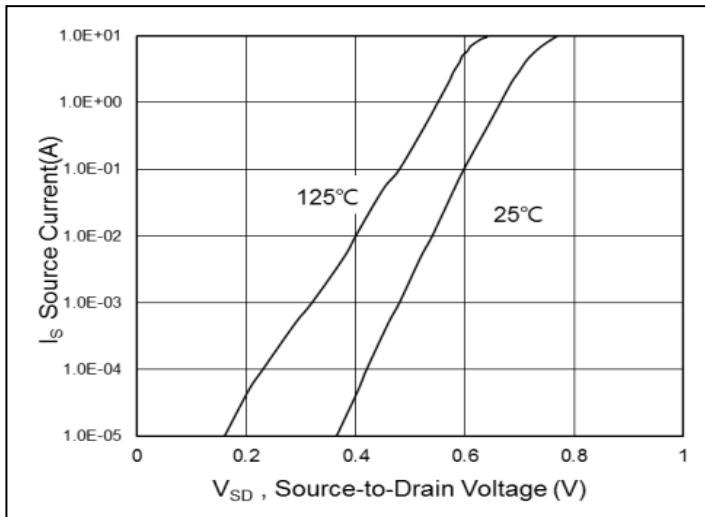


Figure3. Source- Drain Forward Characteristics

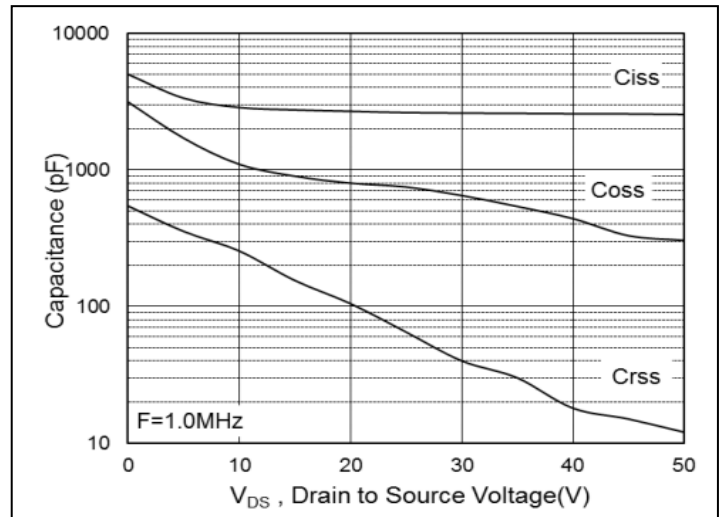


Figure4. Capacitance

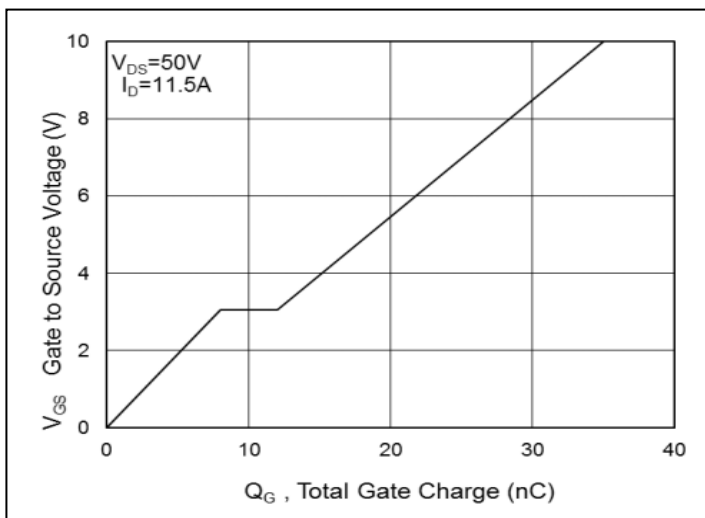


Figure5. Gate Charge

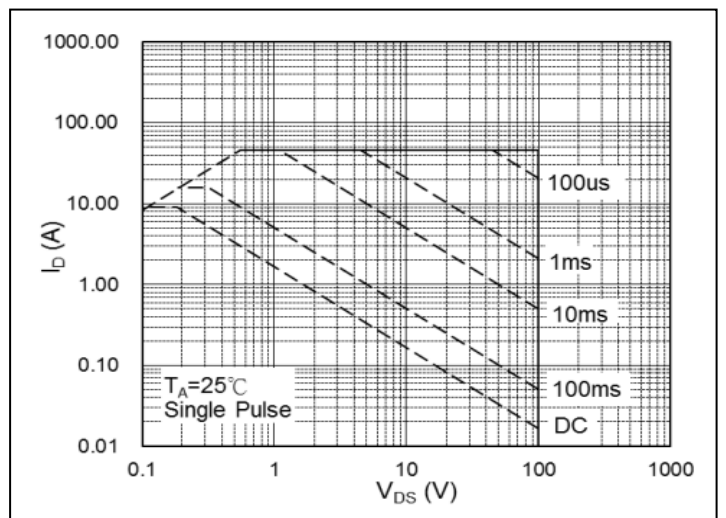


Figure6. Safe Operation Area

Typical Electrical and Thermal Characteristics

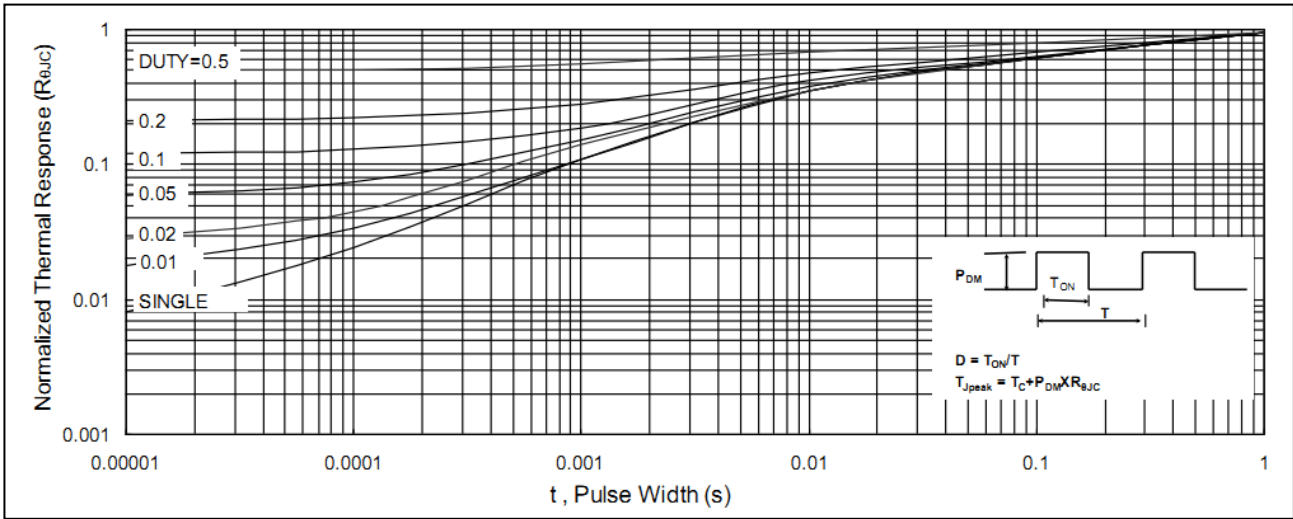
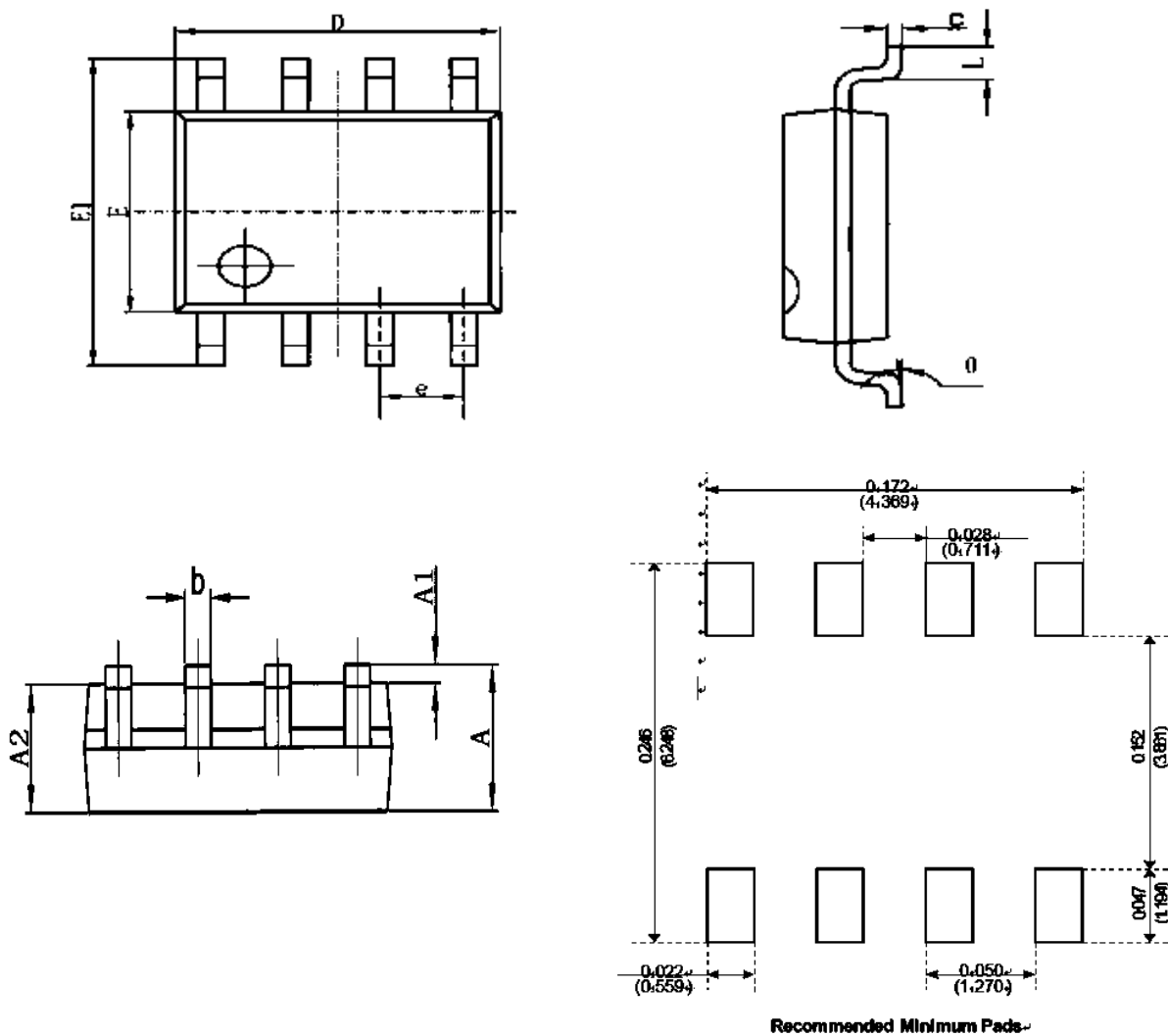


Figure7.Transient Thermal Impedance

Mechanical Data:



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

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